



OCXO Part No: OS560-2005-012

Issue 2; 6th May 2022

Features

- Temperature stability ±5ppb
- Low phase noise
- Frequency 20MHz
- Low pre-aged options available
- The flexible nature of the design means that variations to suit almost any application can be developed to meet individual customer requirements



Temperature stability: ±5ppb over (0 to +50)°C

Output: Sinewave 7dBm nominal Voltage: 5.0V Warm up current: 520mA Quiescent current: 220mA



F0₀+10Hz -128 dBc/Hz F0₀+100Hz -145 dBc/Hz F0₀+1KHz -155 dBc/Hz F0₀+10KHz -160 dBc/Hz F0₀+100KHz -168 dBc/Hz

Values based on 10MHz unit

Voltage / Load change

±5% supply voltage change: ±2ppb

±10% load change: ±10ppb

Ageing

After 30 days continuous operation:

Per day: ±0.1ppb max.

Per year: ±50ppb max.

Warm up time: 5 minutes to within 0.1 ppm

Voltage Trim

±0.5ppm minimum

Trim impedance $50K\Omega$

Reference Options

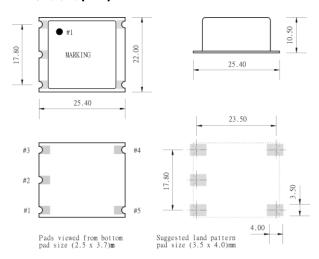
3.0V or 4.5V

Environmental

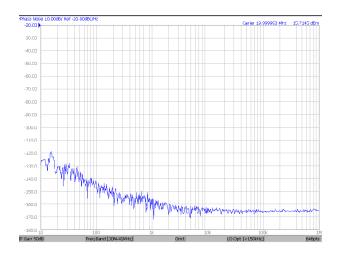
- Electrostatic-Sensitive Device (ESD)
- Storage Temperature Range: (-40 to +125)°C
- Mechanical shock: MIL standard 202, method 213, condition J



Dimensions (mm)



Phase Noise Plot



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- Thermal shock: MIL standard 202, method 107, condition A
- Vibration: MIL standard 202, method 204, condition B
- Solderability: 5 seconds maximum at 230°C
- 3 seconds maximum at 350°C

Compliance

- RoHS Status (2011/65/EU) Compliant
- **REACH Status Compliant**

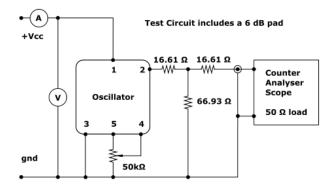
Packaging

Pack Style: Bulk

Ordering Information

- Unique customer part number and custom specification issued with each application
- OCXO Part No: 0S560-2005-012
- Frequency: 20MHz

Test Circuit - Sinewave



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